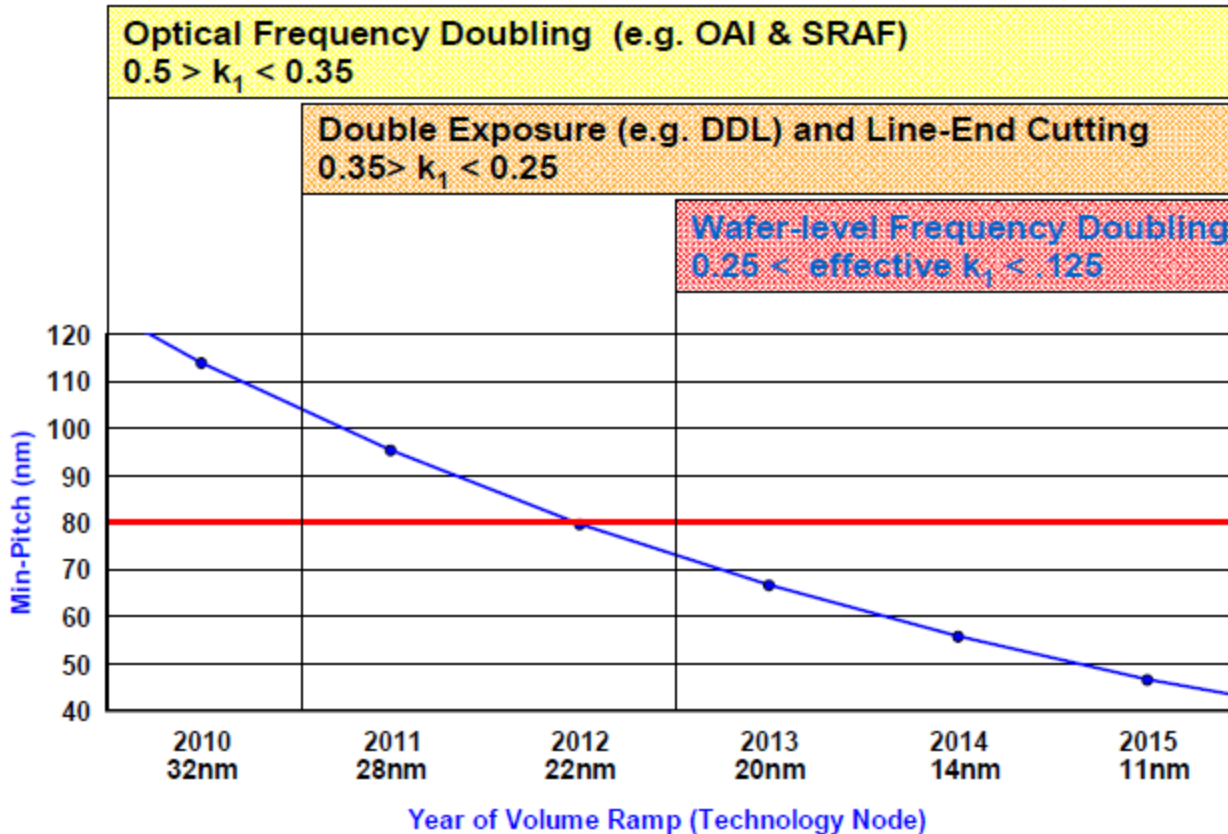


SPIE'11 Review

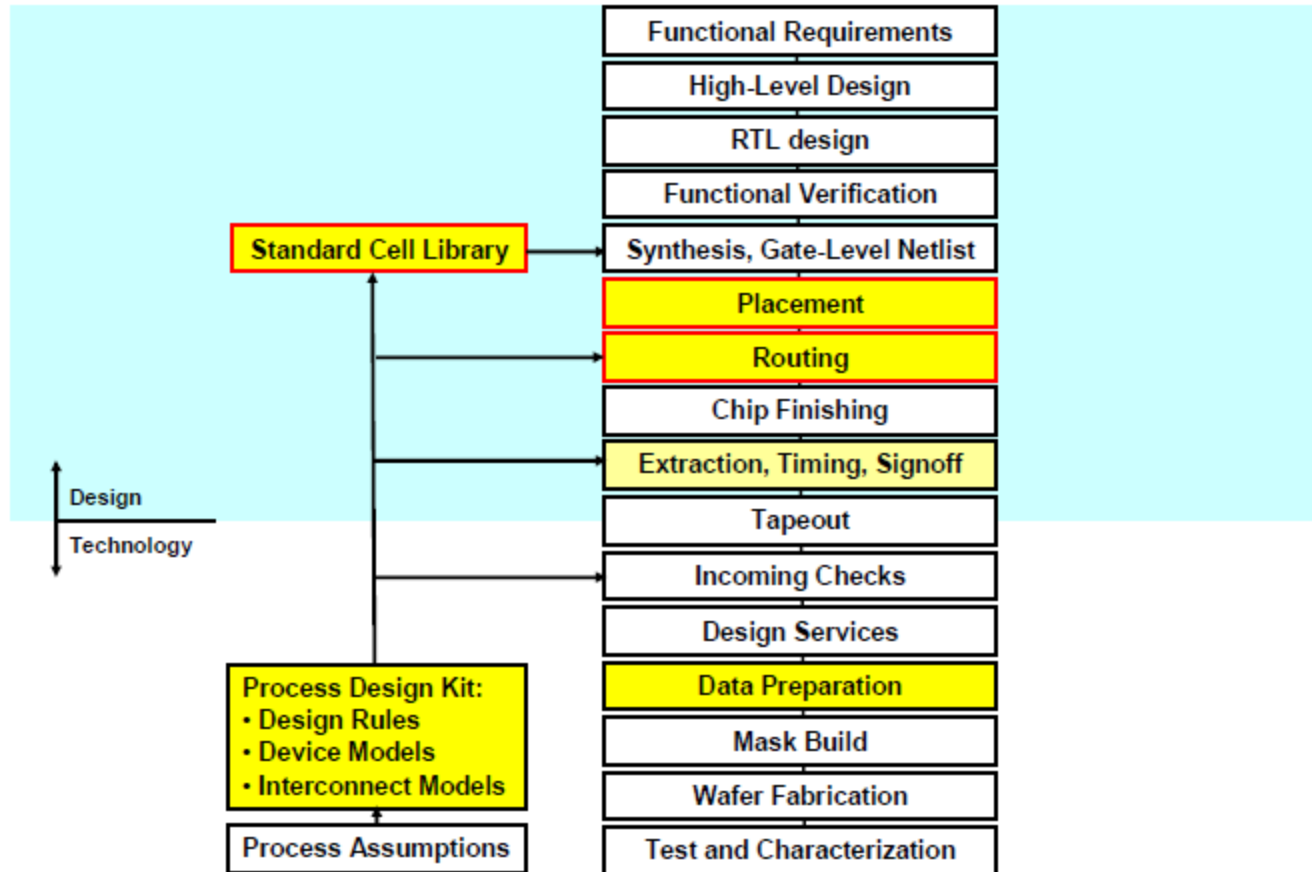
Rani S. Ghaida

Decomposition-Aware Standard Cell Design Flows to Enable DPT (IBM)

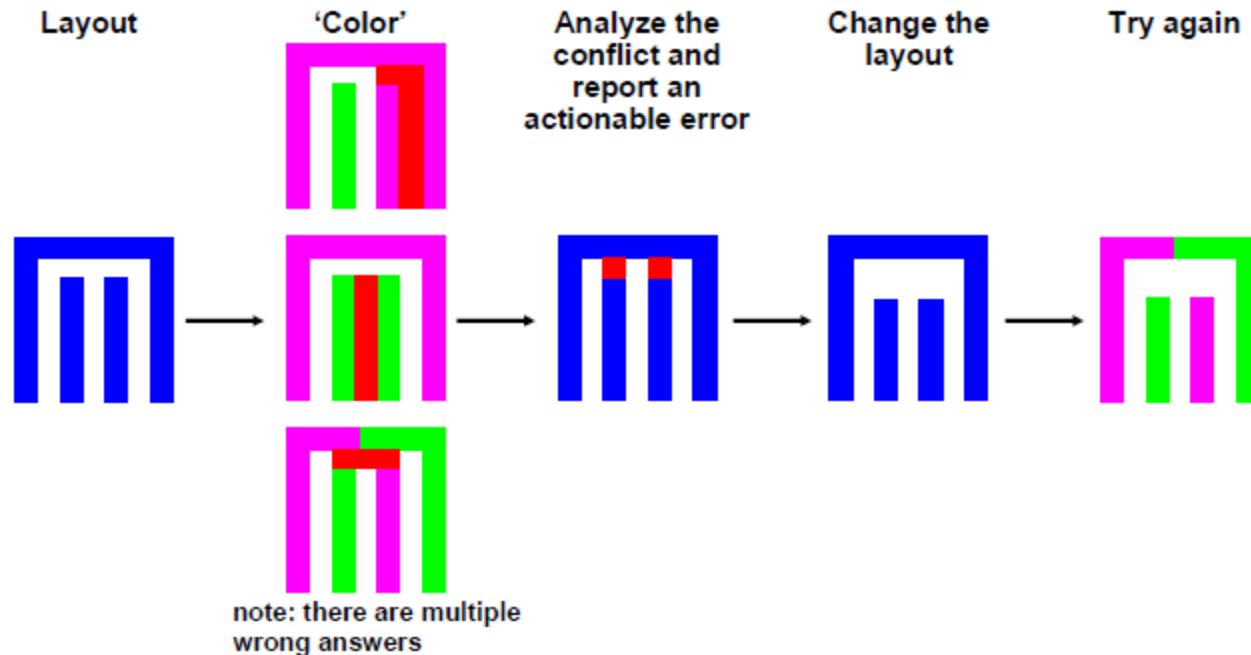


- DPT unavoidable below 80nm pitch

Design-Flow Components Affected by DPT



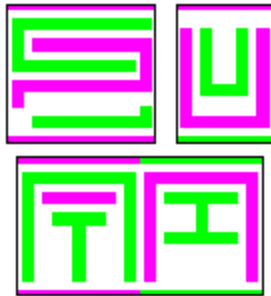
DP Decomposition and Issues



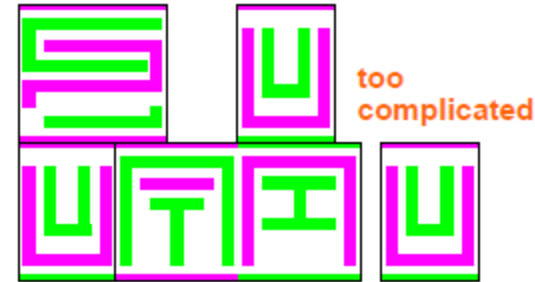
- Need DP decomposition that will eliminate layout legalization inefficiency
 - Decomposition for easy-to-fix conflicts (work in progress)

DP Placement – Extreme approaches

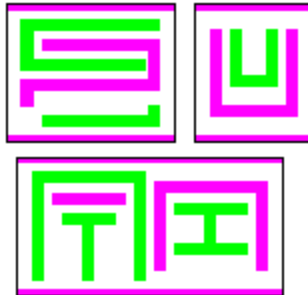
no abutment rules:



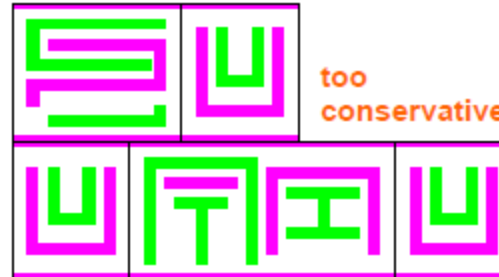
conflicts avoided with smart placement



full set of abutment rules:



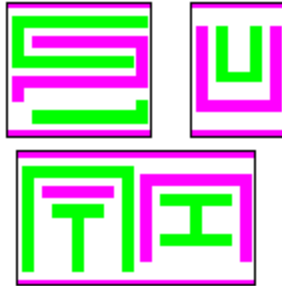
arbitrary placement guaranteed to be clean



*15% area
overhead with
50% logic-cell util*

DP Placement – Hybrid Approaches

horizontal boundaries fixed,
vertical boundaries free,
permanent colors:

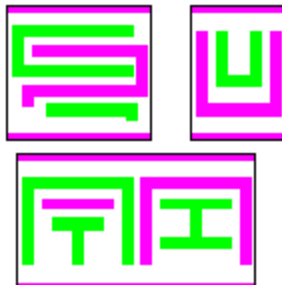


conflicts avoided with smart placement

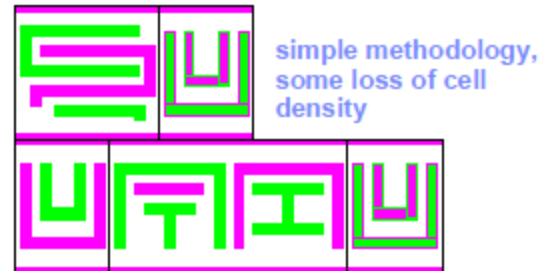


*As low as 2-3%
area overhead*

horizontal boundaries fixed,
vertical boundaries constrained,
temporary colors:



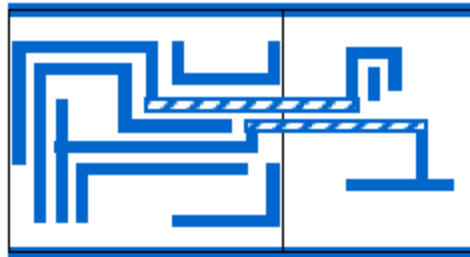
arbitrary placement guaranteed to be colorable
with selective color reversal



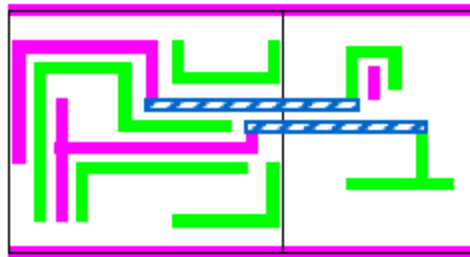
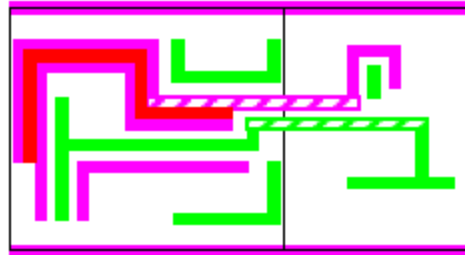
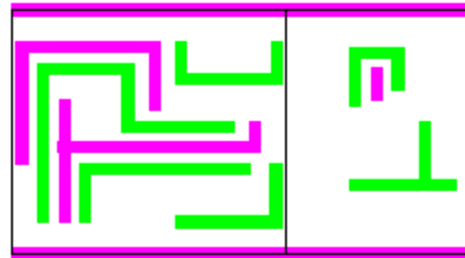
*Some infeasible
cells, need large
cell-height*

1. Only worry about conflicts at vertical boundary, by either filler cells or flipping color (if possible)
2. Power pre-assigned, cell right forced to one color, flippable color w.r.t. power
 - Post-placement coloring or have two versions for each cell and placer chooses

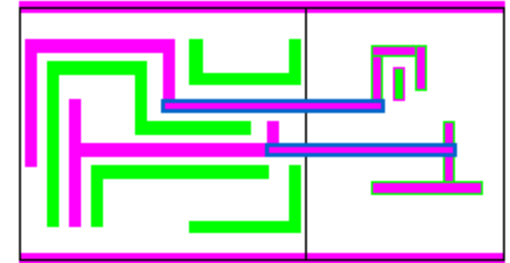
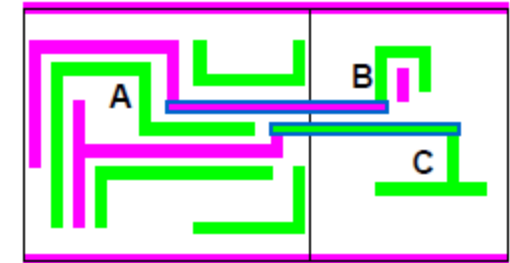
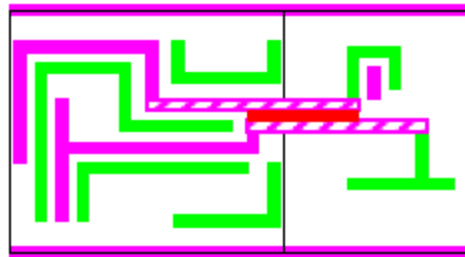
DP Routing



1) re-color after routing:
introduces errors
in previously
clean cells

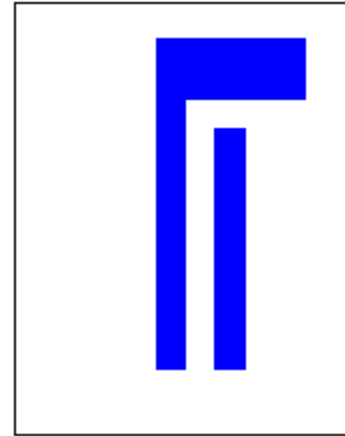
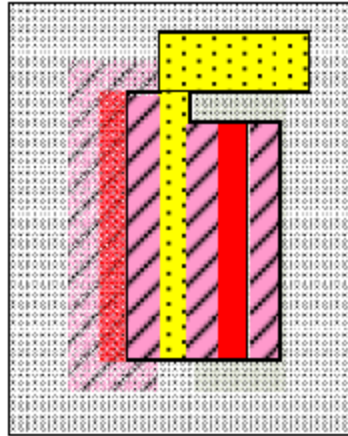


2) rigidly anchor
router-colors to
cell-level colors:
over constrains
the routing
challenge



- Typical iterative optimization involving cycles of coloring, checking, locally re-routing, re-coloring, and re-checking.
- *“To avoid additional routing complexity from DPT, initial design flows will prevent routers from sharing wiring levels that are used predominantly in the cell level design.” (also with globalfoundries)*
 - Eliminates DPT specific cell-to-router issues
 - May not be a long term solution

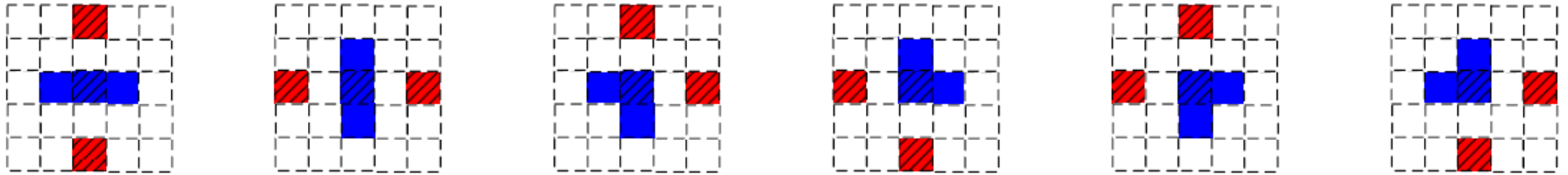
SADP Friendly Detailed Routing (Mentor)



000	000	000	000	000	000	000	000	000
001	001	001	001	001	001	001	001	000
001	111	111	111	111	111	111	001	000
011	111	110	110	110	110	111	011	000
011	111	111	111	111	111	111	011	000
011	111	101	101	101	101	111	011	000
010	111	111	111	111	111	111	010	000
010	010	010	010	010	010	010	010	000
000	000	000	000	000	000	000	000	000

- RMT bits
- Routing variable (R):
 - 1 → already occupied and routing blockage grids
- Mandrel-blocked variable (M):
 - 1 → conflicting on mandrel
- Trim-blocked variable (T):
 - 1 → conflicting on trim

Some Details



- Protective grid: trim grids that can provide assist spacer if filled with mandrel
- Bare grid: **occupied** trim grid is bare if its protective grids are “don’t cares”
 - Assign to trim or mandrel?
- Calculate hesitation parameters for each grid (likelihood)
- Heuristic to find path with best cost for each net (min WL, WL on each mask)

Table 2: Performance comparison between SADP-blind approach and SADP-DR

Design	Area (μm^2)	Nets	Router	Wirelength (nm)	SADP statistics (nm)				Runtime ($sec.$)	Ratio	
					M	PT	BT	Failure		BT	time
d1	410.292	672	blind-DR	8352	5344	984	1448	576	30.2	0.33	1.59
			SADP-DR	8416	3584	4320	512	96			
d2	5581.594	10891	blind-DR	43713	21729	5632	10208	61444	1523.88	0.3	1.65
			SADP-DR	44512	20416	20544	3552	1024			

Double Patterning Compliant Logic Design

(Globalfoundries, cadence, AM)

Litho-Etch-Litho-Etch			Sidewall Spacer SADP		
Begin	TiN Metal Hardmask		Begin	TiN Metal Hardmask	
2	Scanner	ASML 1950i NXT	2	Scanner	ASML 1900i
7	Scanner	ASML 1950i NXT	4	Spacer Dep	PE-ALD on SOC
End	Queued for Via litho		8	Scanner	ASML 1900i
			End	Queued for Via litho	

- 1900i cheaper less overlay accuracy
- 1950i slightly better throughput → almost same cost
- Spacer deposition → \$14-\$22 more per 12" wafer for 4 metal layers
 - Need 0.5%-1% less die area for same overall cost